Spectroscopic Ellipsometers
光谱型椭偏仪

Spectroscopic Ellipsomter(SE) is a multifunction thin film metrology tool to support R&D.
SEMILAB 光谱型椭偏仪是多功能薄膜测试系统，适合各种薄膜材料的研究。

SE-2000

Different tools:

- SE-2xxx-Tabletop to fully automatic system
  SE-2xxx-全自动测试平台
- IRSE-Infrared Spectroscopic Ellipsometry
  IRSE-红外光谱型椭偏仪
- SE-1000-cost effective tabletop tool to manual system
  SE-1000-低成本手动测试平台
- SE-1100-tabletop tool to flexible subtract material
  SE-1100-适于测试柔性衬底材料
- EP-Ellipsometry Porosimeter
  EP-椭偏测孔隙率
- LE-103PV-Laser Ellipsometry
  LE-103PV-激光型椭偏仪

Application:

Photonics:
- LED, AlGaN, GaN, InP, GaAs
- Reflective Coatings, ARC, Ⅲ-Ⅴ devices(EEL, VCSEL, ECL)
- MEMS
- Sol-Gel

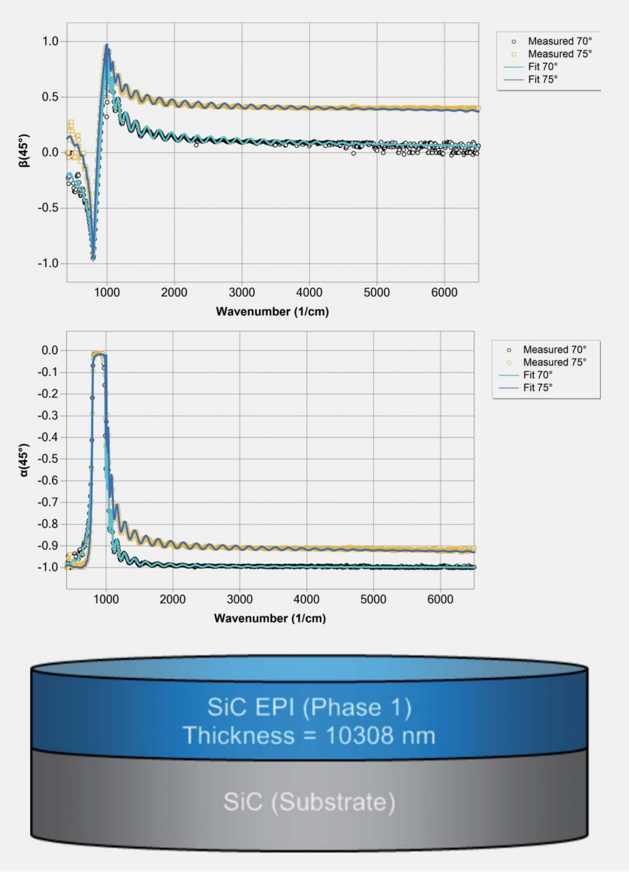
Photovaltage
- Thin films and silicon solar cell, Nanostructure Cells
- Transparent conductive oxide, Nano dots, Nanowires, CNT

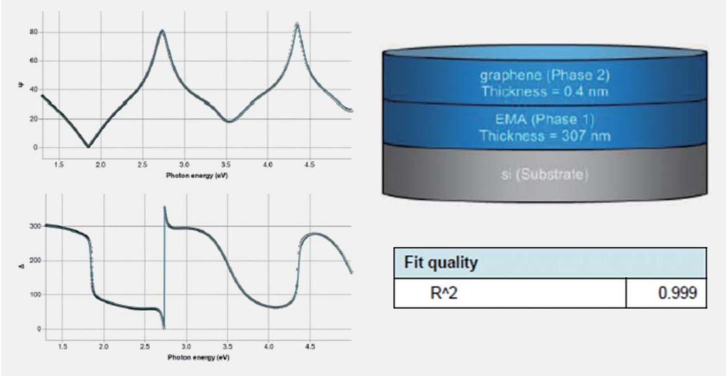
Organics:
- OLED , OPV, Sensors, OTFT

Semiconductors:
- High-k, Gate Oxide , Nitride oxide , Low-k
- Interconnects . Lithography thin films
- Epi-layers : SOI , SiGe , Strained Si, SiC, Poly

Flat Panel Displays:
- TFT-LCD , LTPS , IGZO, OLED, electrochromic layers

General:
- Ferroelectric materials(BST,SBT,PZT)
- Fuel Cells , SOFC , Porous electrode
- Graphene
- 3D materials , periodic structures





Fit quality	
R^2	0.999